

<b>Notice of References Cited</b>	Application/Control No. 09/931,125	Applicant(s)/Patent Under Reexamination ROONEY ET AL.	
	Examiner Marshall S Eng	Art Unit 2133	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,961,653	10-1999	Kalter et al.	714/718
	B	US-5,588,115	12-1996	Augarten, Michael H.	714/718
	C	US-6,643,807	11-2003	Heaslip et al.	714/719
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Schanstra et al., Semiconductor manufacturing process monitoring using built-in self-test for embedded memories, October 1998, International Test Conference proceedings 1998, pp 872-881.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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